IN THE CLAIMS

The following claims are pending in the present application:

1. (Original) A charge coupled device (CCD) comprising a semiconductor

body, a set of storage electrodes separated from the semiconductor body by a

dielectric, and a back electrode, wherein the semiconductor body comprises

polymer or oligomer material and the back electrode forms a Schottky junction

with the semiconductor body by virtue of which the semiconductor body is

depleted of majority charge carriers, so that when in use the storage electrodes

are charged such as to attract the majority charge carriers, they create storage

sites in the semiconductor body which can take either of a first state, in which

there is an accumulation of majority charge carriers at the site, and a second

state, in which such an accumulation is not present at the site.

2. (Original) A CCD as claimed in claim 1 which further comprises shift

electrodes arranged between storage electrodes and separated from the

semiconductor body by a dielectric, by means of which charge can be moved

from one storage site in the semiconductor body to another.

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3. (Previously Presented) A CCD as claimed in claim 1 wherein the back electrode is disposed on one side of the semiconductor body and the storage

electrodes are disposed on the opposite side.

4. (Previously Presented) A CCD as claimed in claim 1 wherein the

semiconductor body is a thin layer at one face of which is the back electrode and

at the other face of which are the storage electrodes and their associated

dielectric.

5. (Original) A CCD as claimed in claim 4 wherein the region of majority

charge carrier depletion created by the said Schottky junction extends through

the full depth of the semiconductor body.

6. (Previously Presented) A CCD as claimed in claim 1 wherein the said

Schottky junction provides a potential barrier to injection of majority charge

carriers to the semiconductor body which is 10kT or greater, where K is

Boltzmann's constant and T is the device's intended operating temperature in

degrees Kelvin.

7. (Previously Presented) A CCD as claimed in claim 1 wherein the back

electrode is metal.

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- 8. (Previously Presented) A CCD as claimed in claim 1 wherein the polymer or oligomer material is conjugated.
- 9. (Previously Presented) A CCD as claimed in claim 1 wherein the semiconductor body comprises poly-3-hexylthiophene.
- 10. (Previously Presented) A CCD as claimed in claim 1 which further comprises a data input structure comprising an input electrode arranged adjacent a storage site in the semiconductor body to cause injection of majority charge carriers thereto.
- 11. (Original) A CCD as claimed in claim 10 wherein the input electrode forms a Schottky junction with the semiconductor body and the data input structure further comprises a transfer electrode adjacent the input electrode, such that applying to the transfer electrode a charge opposite to that of the majority charge carriers in the semiconductor body causes injection of majority charge carriers to a potential well formed in the semiconductor body by the transfer electrode.
- 12. (Original) A CCD as claimed in claim 10 in which data is encoded by provision of input electrodes adjacent to selected storage electrodes, so that upon

initialisation an accumulation of holes is injected to the storage sites corresponding to the selected storage electrodes and not to others.

13. (Original) A CCD as claimed in claim 12 wherein the input electrodes are

connected to a common electrical line so that the device is initialised by applying

an electrical potential to the line in order to drive majority charge carriers into the

selected storage sites.

(Previously Presented) A CCD as claimed in claim 1 wherein the

semiconductor body comprises p type material and is adapted to be driven by

application of negative potentials to the storage electrodes creating sites for hole

accumulation in the semiconductor body.

15. (Previously Presented) A CCD as claimed in claim 1 wherein alternating

storage and shift electrodes are arranged to form a line along which majority

charge carrier accumulations are passed in use.

16. (Previously Presented) A CCD as claimed in claim 15 wherein the line of

electrodes is addressed through first and second electric shift lines and comprises

a series of electrode pairs each comprising a lower field shift electrode electrically

connected to an adjacent higher field storage electrode, alternate such electrode

pairs being electrically connected to the first and second shift lines respectively,

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such that by changing from time to time which of the shift lines is at more negative electrical potential, accumulations of majority charge carriers are passed

along the line of electrodes.

17. (Previously Presented) A CCD as claimed in claim 1 wherein the shift

electrodes are formed by a plurality of localised metal layers which are anodized

to form an oxide layer which is the dielectric by which they are isolated from the

semiconductor body.

18. (Previously Presented) A CCD as claimed in claim 17 wherein the

semiconductor body comprises a layer of polymer or oligomer deposited over

the metal layers.

19. (Previously Presented) A CCD as claimed in claim 1 connected to clocking

circuitry which applies clocked negative potentials to the storage electrodes.

20. (Withdrawn) A method of manufacturing a CCD comprising:

forming upon a substrate a first localised metal layer to serve as a first set of

electrodes:

anodising the first metal layer to form an oxide layer upon it;

forming a second localised metal layer to serve as a second set of electrodes;

anodising the second layer to form an oxide layer upon it;

forming over the metal layers a semiconductor body of polymer or oligomer

material; and

forming upon the semiconductor body a metal back electrode, the material

of the back electrode and of the semiconductor body being such that together

they form a Schottky junction by virtue of which the semiconductor body is

depleted of majority charge carriers.

21-22. (Cancelled)